



YOUSHANG SEMICONDUCTOR

**设计研发新型功率器件**

**各类小信号开关**

**中低压及高压大电流等场效应管**

0755-83047638  
ysbdt@szyoushang.cn  
www.szyoushang.cn



企业微信二维码



企业QQ二维码

## Product Summary

$BV_{DSS}$	$R_{DS(ON)}$ MAX	$I_D$ MAX $T_c = +25^\circ C$ (Note 9)
60V	3.1m $\Omega$ @ $V_{GS} = 10V$	100A

## Features

- 100% Unclamped Inductive Switching (UIS) Test in Production – Ensures More Reliable and Robust End Application
- Low  $R_{DS(ON)}$  – Minimizes Power Losses
- Low  $Q_g$  – Minimizes Switching Losses

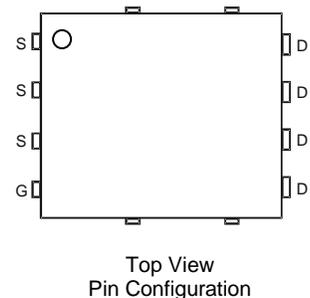
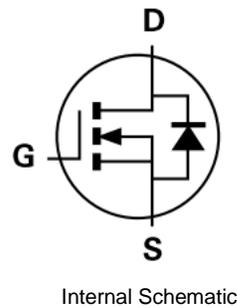
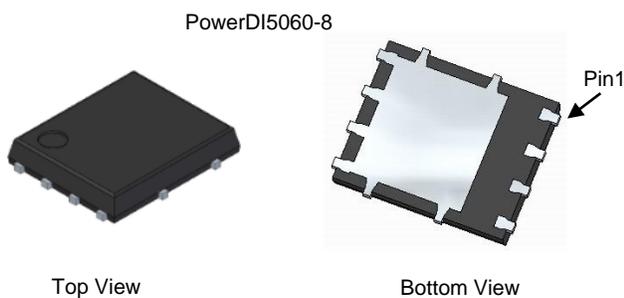
## Description and Applications

This MOSFET is designed to minimize the on-state resistance ( $R_{DS(ON)}$ ) yet maintain superior switching performance, making it ideal for high-efficiency power-management applications.

- Switching
- Synchronous rectifications
- DC-DC converters

## Mechanical Data

- Package: PowerDI<sup>®</sup>5060-8
- Package Material: Molded Plastic, "Green" Molding Compound; UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Finish – Matte Tin Annealed over Copper Leadframe; Solderable per MIL-STD-202, Method 208<sup>③</sup>
- Weight: 0.097 grams (Approximate)



**Maximum Ratings** (@ $T_A = +25^\circ\text{C}$ , unless otherwise specified.)

Characteristic			Symbol	Value	Unit
Drain-Source Voltage			$V_{DSS}$	60	V
Gate-Source Voltage			$V_{GS}$	$\pm 20$	V
Continuous Drain Current (Note 5)	Steady State	$T_A = +25^\circ\text{C}$	$I_D$	23	A
		$T_A = +70^\circ\text{C}$		18	
Continuous Drain Current (Notes 6 & 9)		$T_C = +25^\circ\text{C}$	$I_D$	100	A
		$T_C = +70^\circ\text{C}$		100	
Maximum Continuous Body Diode Forward Current (Notes 6 & 9)			$I_S$	100	A
Pulsed Drain Current (10 $\mu\text{s}$ Pulse, Duty Cycle = 1%)			$I_{DM}$	400	A
Pulsed Body Diode Forward Current (10 $\mu\text{s}$ Pulse, Duty Cycle = 1%)			$I_{SM}$	400	A
Avalanche Current, $L = 0.2\text{mH}$			$I_{AS}$	45	A
Avalanche Energy, $L = 0.2\text{mH}$			$E_{AS}$	200	mJ

**Thermal Characteristics**

Characteristic		Symbol	Value	Unit
Total Power Dissipation (Note 5)	$T_A = +25^\circ\text{C}$	$P_D$	2.6	W
Thermal Resistance, Junction to Ambient	Steady State	$R_{\theta JA}$	47	$^\circ\text{C/W}$
Total Power Dissipation (Note 6)	$T_C = +25^\circ\text{C}$	$P_D$	139	W
Thermal Resistance, Junction to Case		$R_{\theta JC}$	0.9	$^\circ\text{C/W}$
Operating and Storage Temperature Range		$T_J, T_{STG}$	-55 to +150	$^\circ\text{C}$

**Electrical Characteristics** (@ $T_A = +25^\circ\text{C}$ , unless otherwise specified.)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
<b>OFF CHARACTERISTICS (Note 7)</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	60	—	—	V	$V_{GS} = 0\text{V}, I_D = 1\text{mA}$
Zero Gate Voltage Drain Current	$I_{DSS}$	—	—	1	$\mu\text{A}$	$V_{DS} = 48\text{V}, V_{GS} = 0\text{V}$
Gate-Source Leakage	$I_{GSS}$	—	—	$\pm 100$	nA	$V_{GS} = \pm 20\text{V}, V_{DS} = 0\text{V}$
<b>ON CHARACTERISTICS (Note 7)</b>						
Gate Threshold Voltage	$V_{GS(TH)}$	2	2.5	4	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
Static Drain-Source On-Resistance	$R_{DS(ON)}$	—	—	3.1	m $\Omega$	$V_{GS} = 10\text{V}, I_D = 50\text{A}$
Diode Forward Voltage	$V_{SD}$	—	0.9	1.2	V	$V_{GS} = 0\text{V}, I_S = 20\text{A}$
<b>DYNAMIC CHARACTERISTICS (Note 8)</b>						
Input Capacitance	$C_{iss}$	—	4,556	—	pF	$V_{DS} = 30\text{V}, V_{GS} = 0\text{V}, f = 1\text{MHz}$
Output Capacitance	$C_{oss}$	—	1,383	—		
Reverse Transfer Capacitance	$C_{rss}$	—	105.2	—		
Gate Resistance	$R_g$	—	0.7	—	$\Omega$	$V_{DS} = 0\text{V}, V_{GS} = 0\text{V}, f = 1\text{MHz}$
Total Gate Charge	$Q_g$	—	95.4	—	nC	$V_{DD} = 30\text{V}, I_D = 90\text{A}, V_{GS} = 10\text{V}$
Gate-Source Charge	$Q_{gs}$	—	21.6	—		
Gate-Drain Charge	$Q_{gd}$	—	20.4	—		
Turn-On Delay Time	$t_{D(ON)}$	—	13.2	—	ns	$V_{DD} = 30\text{V}, V_{GS} = 10\text{V}, I_D = 90\text{A}, R_g = 3.5\Omega$
Turn-On Rise Time	$t_R$	—	11.7	—		
Turn-Off Delay Time	$t_{D(OFF)}$	—	31	—		
Turn-Off Fall Time	$t_F$	—	12	—		
Body Diode Reverse Recovery Time	$t_{RR}$	—	50.5	—	ns	$I_F = 50\text{A}, di/dt = 100\text{A}/\mu\text{s}$
Body Diode Reverse Recovery Charge	$Q_{RR}$	—	80.8	—	nC	

- Notes:
- Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1-inch square copper plate.
  - Thermal resistance from junction to soldering point (on the exposed drain pad).
  - Short duration pulse test used to minimize self-heating effect.
  - Guaranteed by design. Not subject to production testing.
  - Package limited.

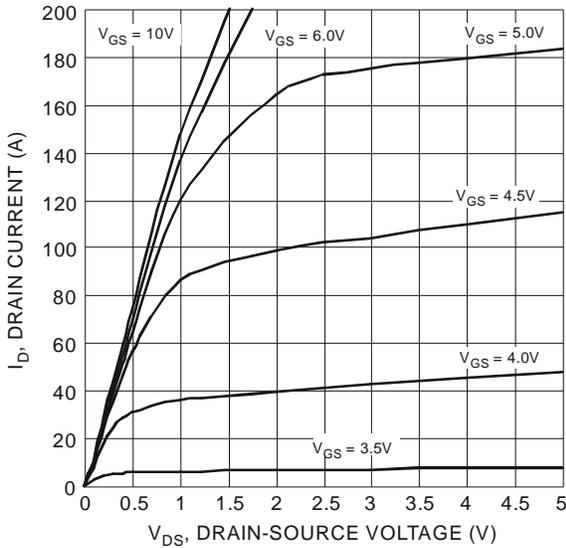


Figure 1 Typical Output Characteristics

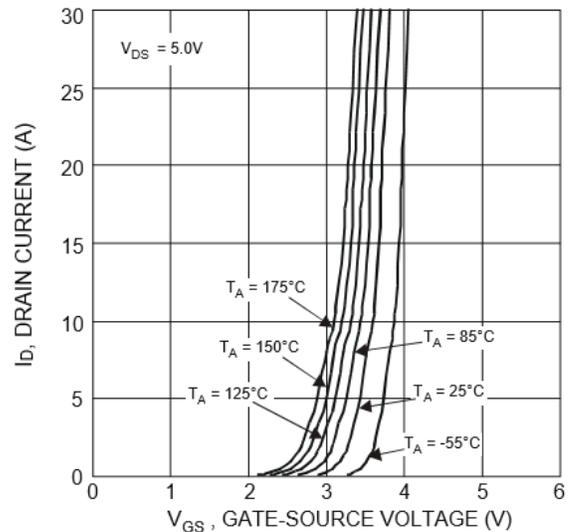


Figure 2 Typical Transfer Characteristics

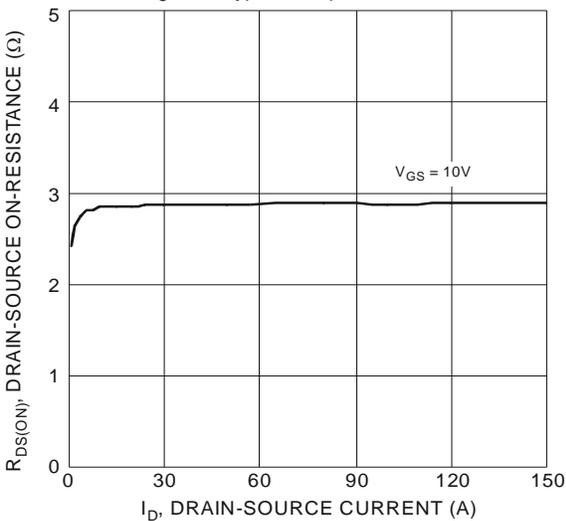


Figure 3 Typical On-Resistance vs. Drain Current and Gate Voltage

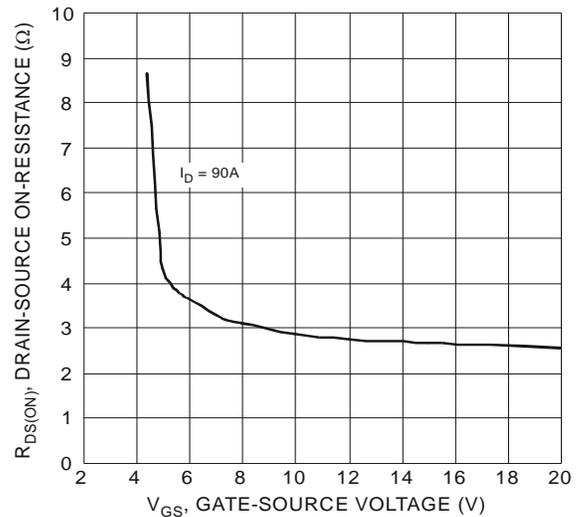


Figure 4 Typical Drain-Source On-Resistance vs. Gate-Source Voltage

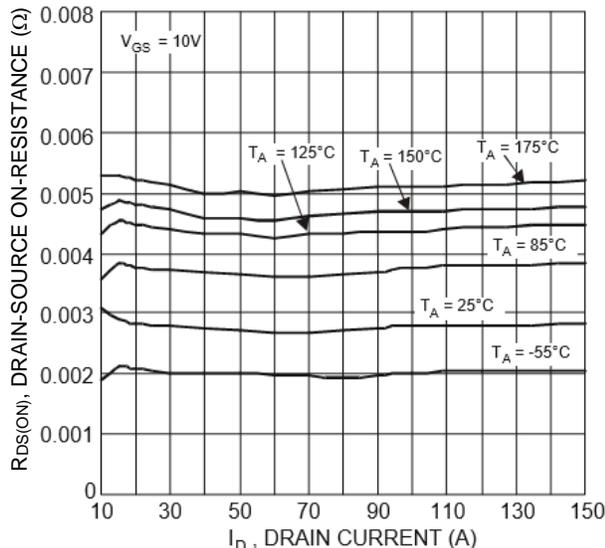


Figure 5 Typical On-Resistance vs. Drain Current and Temperature

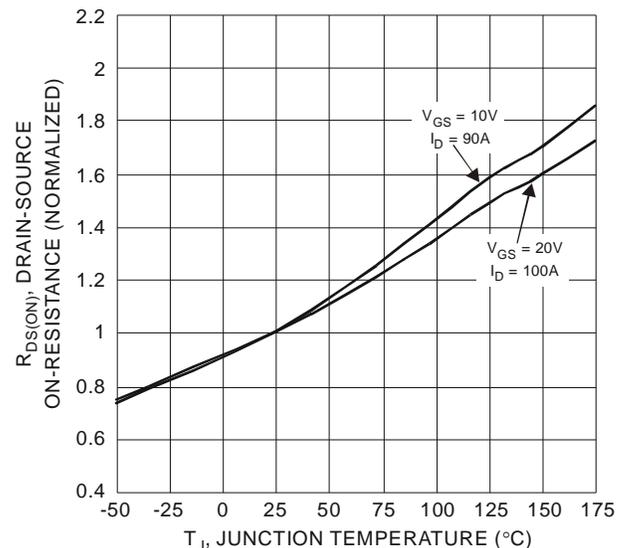


Figure 6 On-Resistance Variation with Temperature

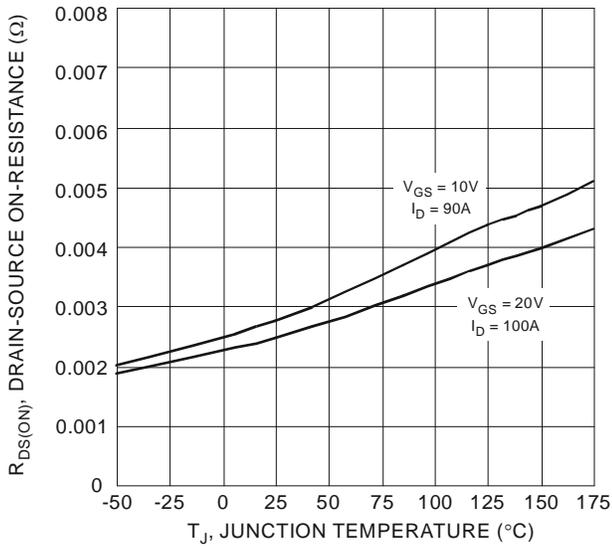


Figure 7 On-Resistance Variation with Temperature

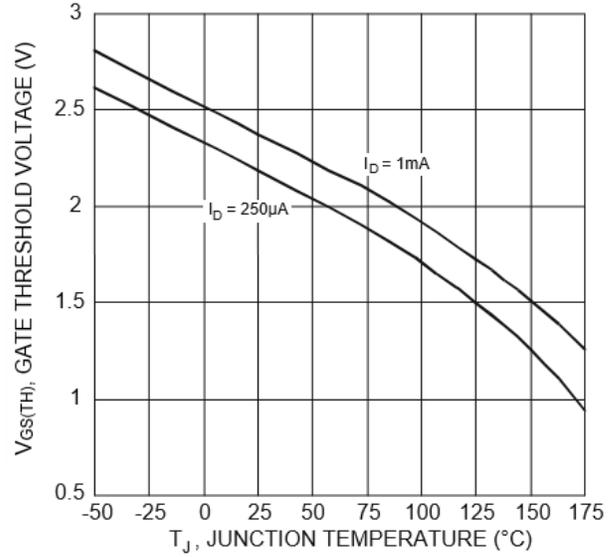


Figure 8 Gate Threshold Variation vs. Junction Temperature

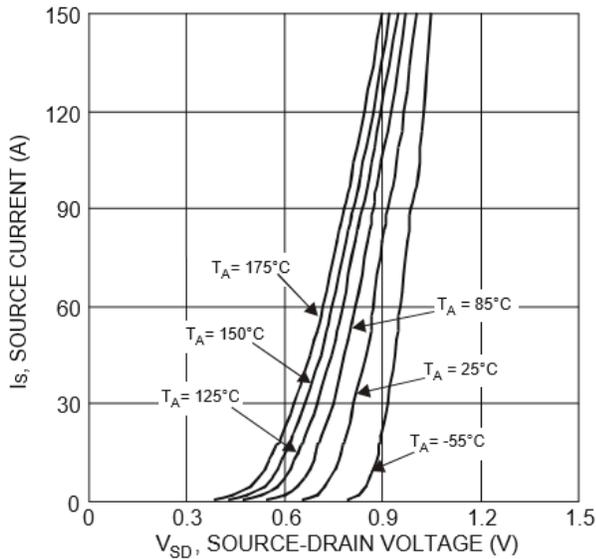


Figure 9 Diode Forward Voltage vs. Current

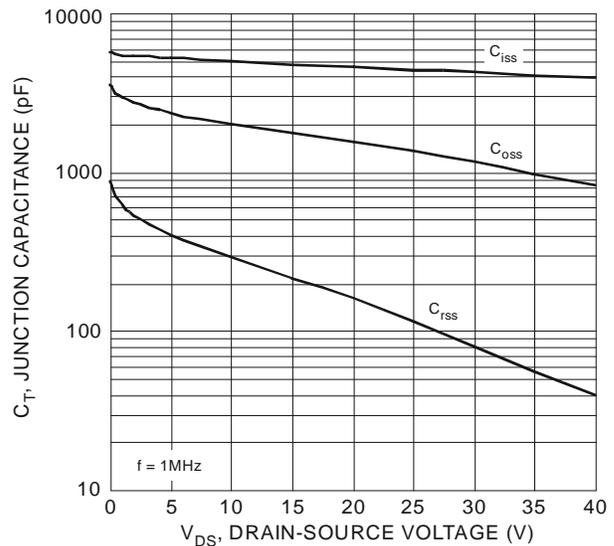


Figure 10 Typical Junction Capacitance

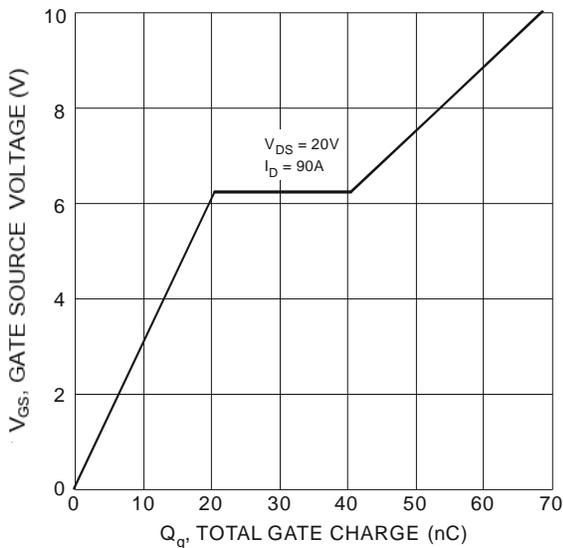


Figure 11 Gate Charge

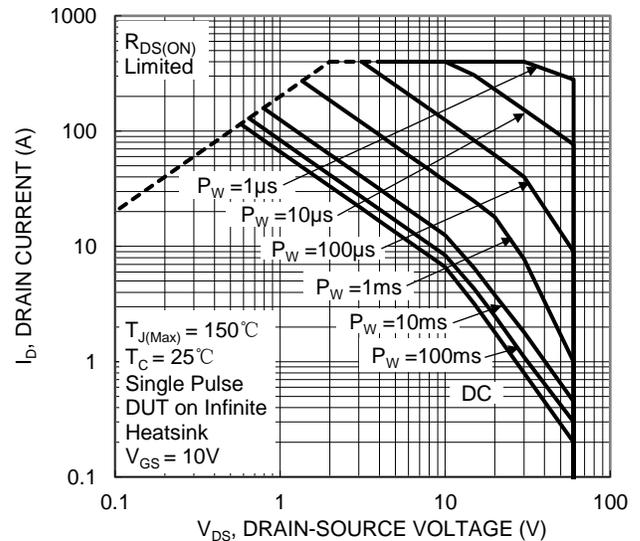


Figure 12 SOA, Safe Operation Area

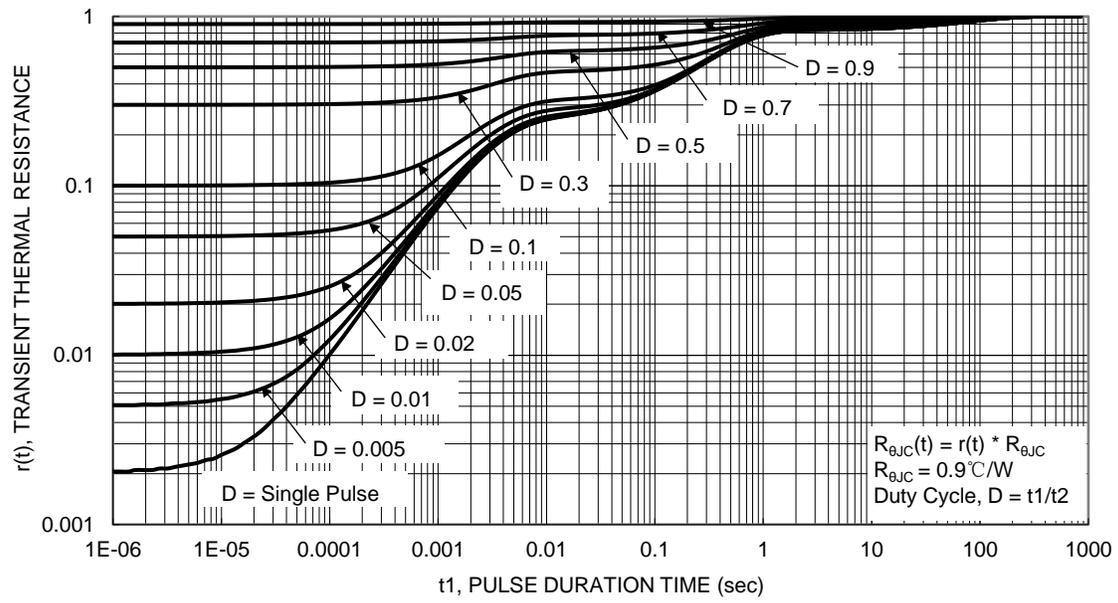
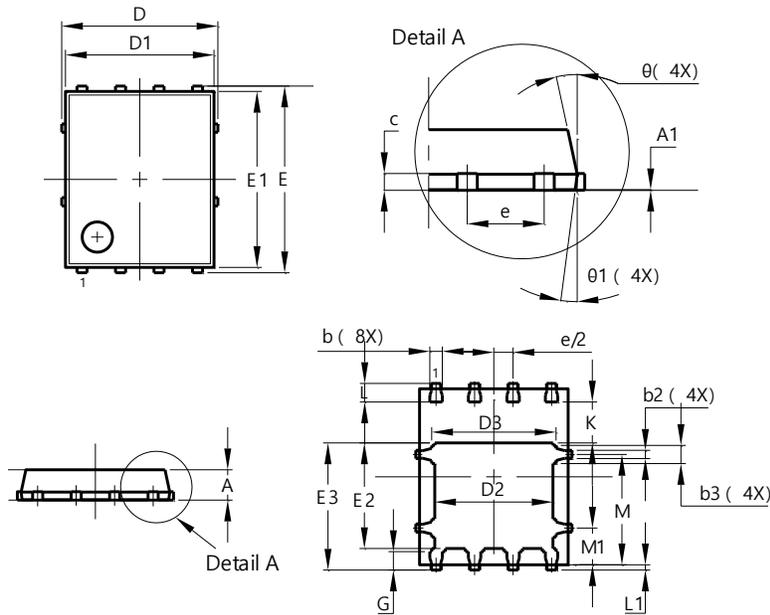


Figure 13 Transient Thermal Resistance

## Package Outline Dimensions

PowerDI5060-8

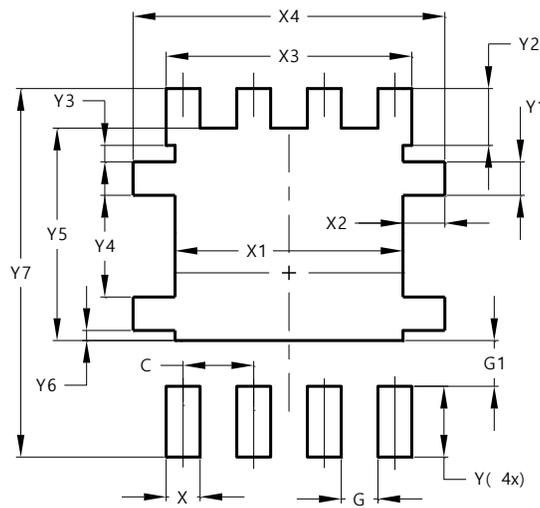


PowerDI5060-8			
Dim	Min	Max	Typ
A	0.90	1.10	1.00
A1	0.00	0.05	—
b	0.33	0.51	0.41
b2	0.200	0.350	0.273
b3	0.40	0.80	0.60
c	0.230	0.330	0.277
D	5.15 BSC		
D1	4.70	5.10	4.90
D2	3.70	4.10	3.90
D3	3.90	4.30	4.10
E	6.15 BSC		
E1	5.60	6.00	5.80
E2	3.28	3.68	3.48
E3	3.99	4.39	4.19
e	1.27 BSC		
G	0.51	0.71	0.61
K	0.51	—	—
L	0.51	0.71	0.61
L1	0.100	0.200	0.175
M	3.235	4.035	3.635
M1	1.00	1.40	1.21
Θ	10°	12°	11°
Θ1	6°	8°	7°

All Dimensions in mm

## Suggested Pad Layout

PowerDI5060-8



Dimensions	Value (in mm)
C	1.270
G	0.660
G1	0.820
X	0.610
X1	4.100
X2	0.755
X3	4.420
X4	5.610
Y	1.270
Y1	0.600
Y2	1.020
Y3	0.295
Y4	1.825
Y5	3.810
Y6	0.180
Y7	6.610